

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Shunzo YAMASHITA, et al

Filed: on even date herewith

For: QUALITY MONITORING SYSTEM FOR BUILDING STRUCTURE,
QUALITY MONITORING METHOD FOR BUILDING STRUCTURE
AND SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE

CLAIM FOR PRIORITY

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

November 14, 2003

Sir:

Under the provisions of 35 USC '119 AND 37 CFR ' 1.55, Applicants hereby
claim the right of priority based on Japanese Patent Application No. 2002-331532
filed November 15, 2002.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP



Alan E. Schiavelli
Registration No. 32,087

AES/nac
1300 North Seventeenth Street
Suite 1800
Arlington, VA 22209
Tel.: 703-312-6600
Fax.: 703-312-6666